Abstract

2   A novel method for finding optimized solutions for assigning pins to probes in a constrained tester environment is presented. Given a test system
4   network, including the nodes, probes, pins, resources, probe-to-resource mappings, resource-to-pin mappings, and test-to-resource mappings, and
6   constraints including a Multiple-Resource-Per-Probe Constraint, a Same-Module Constraint, and/or a Multiplexing Constraint, the test system network
8   is modeled as a Network Flow Problem to handle all of the constraints of the constrained pin-to-probe assignment problem, using "dummy" probes where
10   necessary to model the constrained network. A modified Maximum Flow Algorithm that satisfies the network constraints is applied to the Network
12   Flow Problem to generate a solution to said constrained pin-to-probe assignment problem.